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TEST REPORT

Eurofins KCTL Co.,Ltd. 65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea TEL: 82-70-5008-1021 FAX: 82-505-299-8311 www.kctl.co.kr	Report No.: KR24-SRF0151-B Page (1) of (7)	eurofins | KCTL

1. Client

- Name : Samsung Electronics Co., Ltd.
- Address : 129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea
- Date of Receipt : 2024-09-11

2. Use of Report : Certification

3. Name of Product / Model : Notebook PC / NP750QHA

4. Manufacturer / Country of Origin : Samsung Electronics Co., Ltd. / Vietnam

5. FCC ID : A3LNP750QHA

6. IC Certificate No. : 649E-NP750QHA

7. Date of Test : 2024-10-08 to 2024-10-14

8. Location of Test : ■ Permanent Testing Lab ☐ On Site Testing
(Address:65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea)

9. Test method used : 47 CRF Part 2.1093

10. Test Result : Refer to the test result in the test report

	Tested by	Technical Manager
Affirmation	Name : Hyesom Shin (Signature)	Name : Harim Lee (Signature)

2024-11-04

Eurofins KCTL Co.,Ltd.

As a test result of the sample which was submitted from the client, this report does not guara ntee the whole product quality. This test report should not be used and copied without a written agreement by Eurofins KCTL Co.,Ltd.

REPORT REVISION HISTORY

Date	Revision	Page No
2024-10-28	Originally issued	-
2024-10-28	Device Information update	4
2024-11-04	Update	7

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Note. The report No. KR24-SRF0151-A is superseded by the report No. KR24-SRF0151-B.

General remarks for test reports

Statement concerning the uncertainty of the measurement systems used for the tests

(may be required by the product standard or client)

☐ **Internal procedure used for type testing through which traceability of the measuring uncertainty has been established:**

Procedure number, issue date and title:

Calculations leading to the reported values are on file with the testing laboratory that conducted the testing.

☒ **Statement not required by the standard or client used for type testing**

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1. General information

Client	:	Samsung Electronics Co., Ltd.
Address	:	129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea
Manufacturer	:	Samsung Electronics Co., Ltd.
Address	:	129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Rep. of Korea
Laboratory	:	Eurofins KCTL Co.,Ltd.
Address	:	65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
Accreditations	:	FCC Site Designation No: KR0040, FCC Site Registration No: 687132 VCCI Registration No. : R-20080, G-20078, C-20059, T-20056 CAB Identifier: KR0040 ISED Number: 8035A KOLAS No.: KT231

2. Device information

Equipment under test	:	Notebook PC
Model	:	NP750QHA
Derivative model	:	NP754QHA, NP750QHZ
Modulation technique	:	ASK
Power source	:	DC 15.44 V
Antenna specification	:	Coil Loop Antenna
Frequency range	:	531.25 ~ 593.75 ㎑ (Digitizer)
Software version	:	Windows 11
Hardware version	:	REV1.0
Test device serial No.	:	Radiation: 1S7D91ZX800034F
Operation temperature	:	10 ℃ ~ 35 ℃

2.1. Information for Derivative model

The difference between Main model and Derivative model is as below.

Main model	NP750QHA
Derivative model	NP754QHA, NP750QHZ
Differences	Marketing and logistic difference

2.2. Frequency/channel operations

This device contains the following capabilities:
Digitizer

Frequency (㎑)
531.25 ~ 593.75

Table 2.2.1. Digitizer

3. Worst-Case configuration and mode

Mode	Test Case	EUT State	Description
S-Pen Digitizer	1	Stand-alone	**Button (531.25 ㎑)**
		Stand-alone with TA	
	2	Stand-alone	Writing (562.50 kHz)
		Stand-alone with TA	
	3	Stand-alone	Eraser (593.75 kHz)
		Stand-alone with TA	

Notes:

1. For Digitizer mode, test results of case 1 is worst case, so this test report described test case 1.

4. RF Exposure

Regulation

According to KDB 447498 D01v06, the test exclusion condition is based on source-based time-averaged maximum conducted output power of the RF channel requiring evaluation, adjusted for tune-up tolerance, and the minimum test separation distance required for the exposure conditions. The exclusion threshold is determined by the following formula.

a) For 100 ㎒ to 6 ㎓ and test separation distance ≤ 50mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:

[(max. power of channel, including tune-up tolerance, ㎽) / (min. test separation distance, mm)] · [√f(㎓)] ≤ 3.0 for 1-g SAR, and ≤ 7.5 for 10-g extremity SAR, where,

- f(㎓) is the RF channel transmit frequency in ㎓
- Power and distance are rounded to the nearest ㎽ and mm before calculation
- The result is rounded to one decimal place for comparison
- The values 3.0 and 7.5 are referred to as numeric thresholds in step b) below

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm, and for transmission frequencies between 100 ㎒ and 6 ㎓. When the minimum test separation distance is < 5 mm, a distance of 5mm according to 4.1 f) is applied to determine SAR test exclusion.

b) For 100 ㎒ to 6 ㎓ and test separation distance> 50 mm, the 1-g and 10-g SAR test exclusion thresholds are determined by the following:
   1) {[Power allowed at numeric threshold for 50 mm in step a)] + [(test separation distance – 50 mm)·(f(㎒)/150)]} mW, for 100 ㎒ to 1500 ㎒
   2) {[Power allowed at numeric threshold for 50 mm in step a)] + [(test separation distance – 50 mm)·10]} mW, for> 1500 ㎒ and ≤ 6 ㎓

c) For frequencies below 100 ㎒, the following may be considered for SAR test exclusion:

   1) For test separation distances> 50 mm and < 200 mm, the power threshold at the corresponding test separation distance at 100 MHz in step b) is multiplied by [1 + log(100/f(㎒))]
   2) For test separation distances ≤ 50 mm, the power threshold determined by the equation in c) 1) for 50 mm and 100 ㎒ is multiplied by ½
   3) SAR measurement procedures are not established below 100 ㎒.

4.1. Test results

Calculation Result of RF exposure

Measured Output power

Mode	Frequency [㎒]	MeaE-field [dB㎶/m]	Test Distance [m]	EIRP [dBm]	EIRP [㎽]	Threshold [㎽]
Button	0.531 25	-1.46	30	-76.62	0.000 000 022	834.44

Max. Output power

Mode	Frequency [㎒]	Max. EIRP(including tune-up) [dBm]	Max. EIRP(including tune-up) [㎽]	Threshold [㎽]
Button	0.531 25	-73.00	0.000 000 050	834.44

Note:

1. EIRP (dBm) = E-fild(dB ㎶/m) + 20log(d(m))-104.7
2. EIRP (㎽) = 10^(EIRP(dBm)/10)
3. Threshold;

SAR Test exclusion Threshold according to KDB 447498 D01, appendix C,

Appendix C

***SAR Test Exclusion Thresholds* for < 100 MHz and < 200 mm**

Approximate SAR test exclusion power thresholds at selected frequencies and test separation distances are illustrated in the following table. The equation and threshold in 4.3.1 must be applied to determine SAR test exclusion.

MHz	< 50	50	60	70	80	90	100	110	120	130	140	150	160	170	180	190	mm
100	237	474	481	487	494	501	507	514	521	527	534	541	547	554	561	567	
50	308	617	625	634	643	651	660	669	677	686	695	703	712	721	729	738	
10	474	948	961	975	988	1001	1015	1028	1041	1055	1068	1081	1095	1108	1121	1135	
1	711	1422	1442	1462	1482	1502	1522	1542	1562	1582	1602	1622	1642	1662	1682	1702	mW
0.1	948	1896	1923	1949	1976	2003	2029	2056	2083	2109	2136	2163	2189	2216	2243	2269	
0.05	1019	2039	2067	2096	2125	2153	2182	2211	2239	2268	2297	2325	2354	2383	2411	2440	
0.01	1185	2370	2403	2437	2470	2503	2537	2570	2603	2637	2670	2703	2737	2770	2803	2837	

Conclusion

Because maximum output power value(㎽) for digitizer is less than SAR threshold level (㎽), so SAR test for digitizer can be excluded.

End of test report